

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination HIRAIWA ET AL.	
		Examiner Daniel Kim	Art Unit 2185	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0010733	01-2005	Mimatsu et al.	711/162
	B	US-2002/0078178	06-2002	Senoh, Takanori	709/219
	C	US-6,363,502	03-2002	Jeddeloh, Joseph	714/52
	D	US-2004/0039890	02-2004	Itoh et al.	711/162
	E	US-2003/0200275	10-2003	Hirabayashi et al.	709/214
	F	US-2004/0220975	11-2004	Carpentier et al.	707/200
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.